2SC3311A

Silicon NPN epitaxial planar type

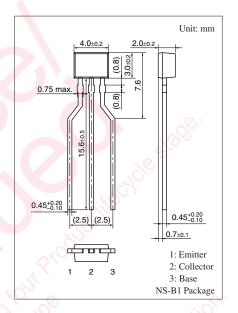
For low-frequency amplification Complementary to 2SA1309A

■ Features

- Optimum for high-density mounting
- Allowing supply with the radial taping

■ Absolute Maximum Ratings $T_a = 25$ °C

| Parameter | Symbol | Rating | Unit |
|---------------------------------------|------------------|-------------|------|
| Collector-base voltage (Emitter open) | V_{CBO} | 60 | V |
| Collector-emitter voltage (Base open) | V_{CEO} | 50 | V |
| Emitter-base voltage (Collector open) | V _{EBO} | 7 | V |
| Collector current | I_{C} | 100 | mA |
| Peak collector current | I_{CP} | 200 | mA |
| Collector power dissipation | P _C | 300 | mW |
| Junction temperature | T_{j} | 150 | °C |
| Storage temperature | T _{stg} | -55 to +150 | °C O |



■ Electrical Characteristics $T_a = 25$ °C ± 3 °C

| Parameter | Symbol | Conditions | Min | Тур | Max | Unit |
|--|----------------------|---|-----|-----|-----|------|
| Collector-base voltage (Emitter open) | V _{CBO} | $I_C = 10 \mu\text{A}, I_E = 0$ | 60 | 95 | | V |
| Collector-emitter voltage (Base open) | V_{CEO} | $I_C = 2 \text{ mA}, I_B = 0$ | 50 | | | V |
| Emitter-base voltage (Collector open) | V_{EBO} | $I_E = 10 \mu A, I_C = 0$ | 7 | | | V |
| Collector-base cutoff current (Emitter open) | I_{CBO} | $V_{CB} = 10 \text{ V}, I_{E} = 0$ | | | 0.1 | μΑ |
| Collector-emitter cutoff current (Base open) | I _{CEO} | $V_{CE} = 10 \text{ V}, I_{B} = 0$ | | | 1 | μΑ |
| Forward current transfer ratio * | h_{FE} | $V_{CE} = 10 \text{ V}, I_{C} = 2 \text{ mA}$ | 160 | | 460 | _ |
| Collector-emitter saturation voltage | V _{CE(sat)} | $I_C = 100 \text{ mA}, I_B = 10 \text{ mA}$ | | 0.1 | 0.3 | V |
| Transition frequency | f_T | $V_{CB} = 10 \text{ V}, I_E = -2 \text{ mA}, f = 200 \text{ MHz}$ | | 150 | | MHz |
| Collector output capacitance | C _{ob} | $V_{CB} = 10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$ | | 3.5 | | pF |
| (Common base, input open circuited) | | 160 K | | | | |

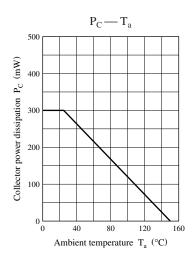
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

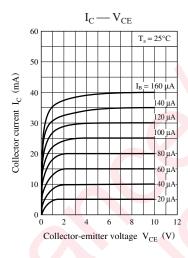
2. *: Rank classification

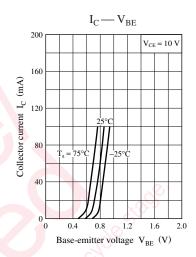
| Rank | Q | R | S | No-rank |
|----------|------------|------------|------------|------------|
| h_{FE} | 160 to 260 | 210 to 340 | 290 to 460 | 160 to 460 |

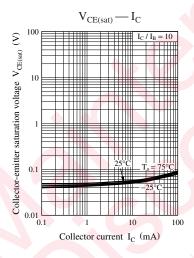
Product of no-rank is not classified and have no indication for rank.

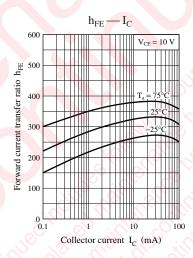
Panasonic

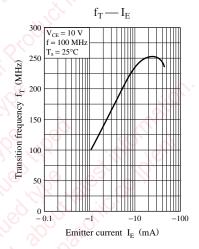


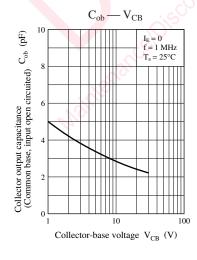


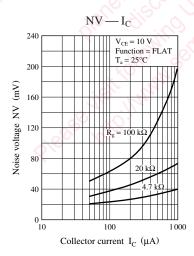












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